Issue	Classification	

Application/Control No.	Applicant(s)/Patent under Reexamination SHINO ET AL.							
10/019,332								
Examiner	Art Unit							
Danny Wai Lun Leung	2633							

	ISSUE CLASSIFICATION																				
ORIGINAL									CROSS REFERENCE(S)												
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January (Date)							JASON CHAN SUPERVISORY PATENT EXAMINER SUPERVISORY OF TER 2600							, –	Total Claims Allo				owed: 6		
(Legar instruments examiner) (Cate)									TECHNOLOGY CENTER 2600 (Primary Examiner) (Date)							Print Claim(s)				Print Fig.	
	☐ Claims renumbered in the same order as presented by applicant ☐ CPA ☐ T.D. ☐												□R.	.1.47							
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